In July 2012, A&D Co., Ltd. exhibited an FIB (focused ion beam) and EB (electron beam) at the Microscopy & Microanalysis Conference in Phoenix, Arizona. This exhibition is one of the biggest within the microscience field. We are sure of its affinity with our products. It was a precious opportunity to expose our company and products in the American market.

Our exhibition was mainly about FIBs, EB columns, and high voltage power supplies.

Pictures

Exhibitor information

A&D Company, Limited

A&D Company Limited is Japan has been manufacturing FIB, SEM, and Scanning Electron Microscope Systems for more than 30 years. A&D FIB and SEM columns are available not only for R&D but also in SEM/FIB system manufacturing such as the FIB/SEM Lithography System EBL-100, FIB accompanying FIB-100S, and Top-SMS systems. Hayward FIB, EB, MV power supply.